

Volume 16, Number 6

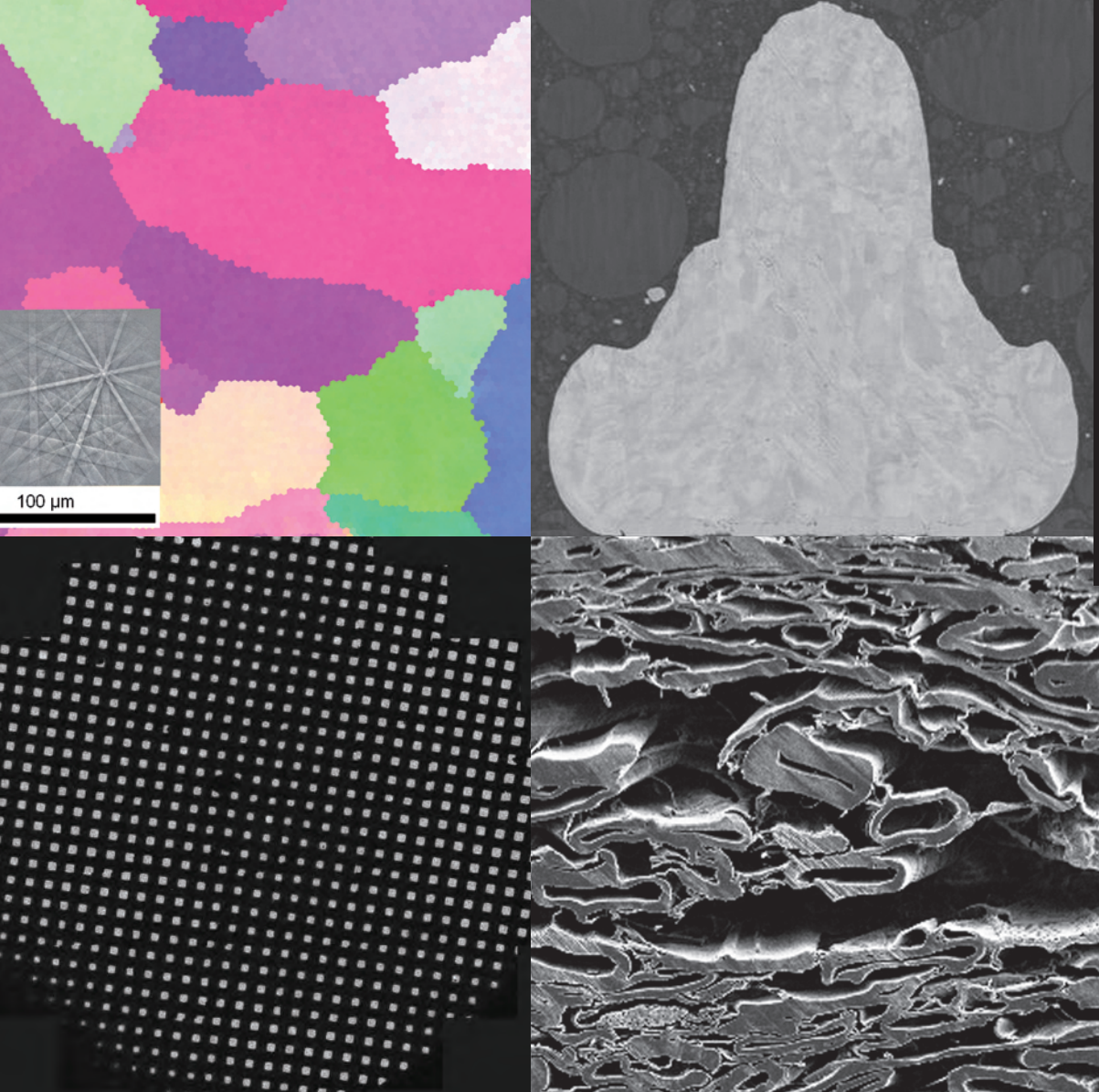
December 2010

Microscopy AND Microanalysis



CAMBRIDGE
UNIVERSITY PRESS

ISSN 1431-9276



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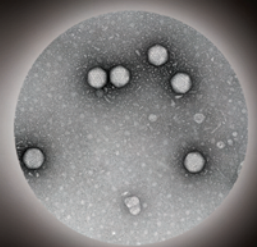
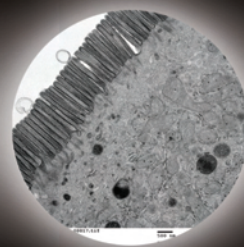
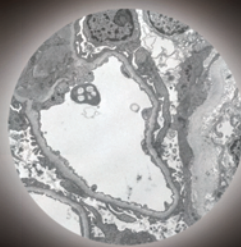
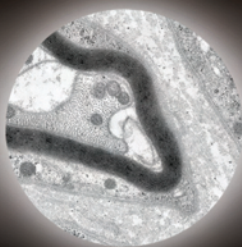
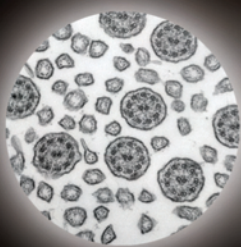
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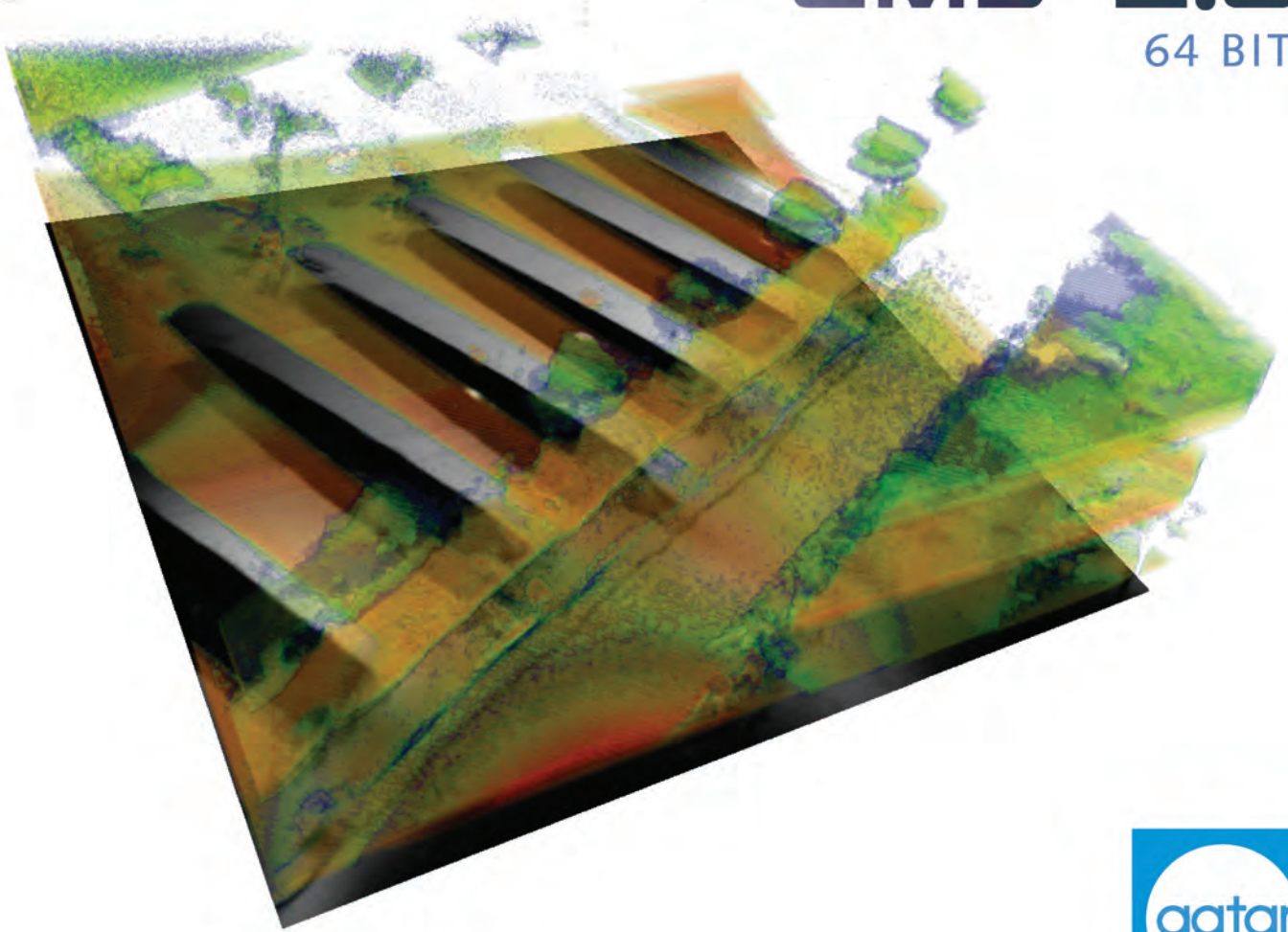


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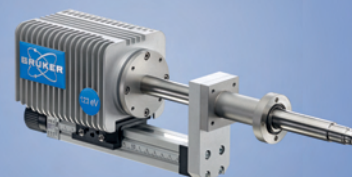
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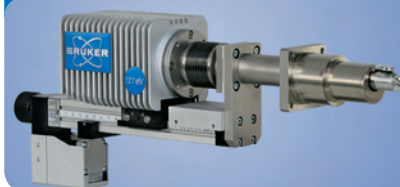
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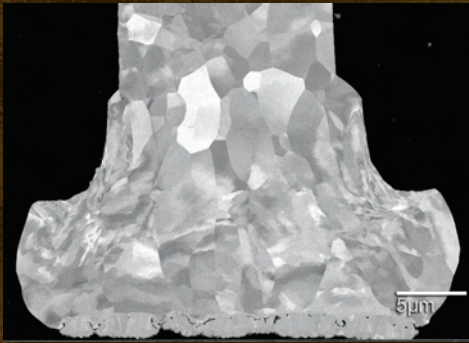
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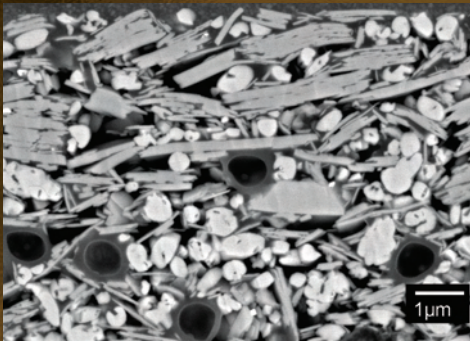
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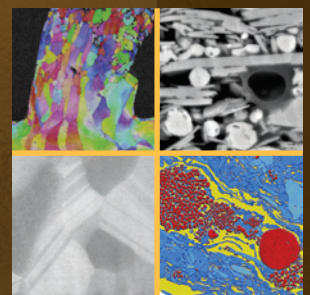


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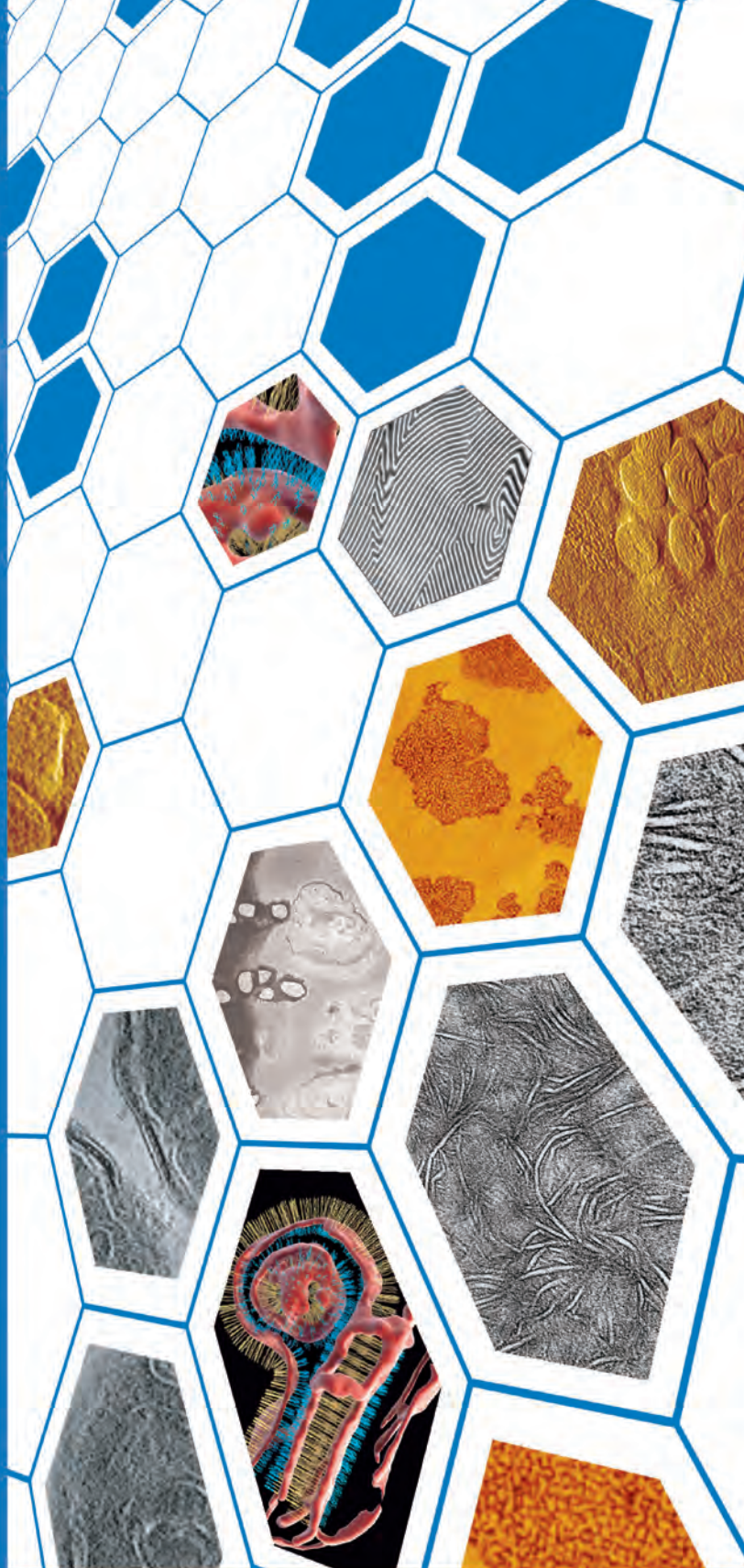
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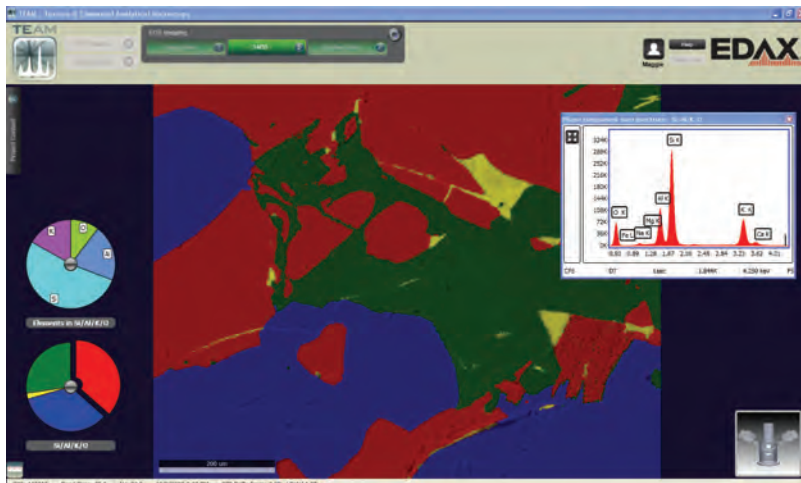
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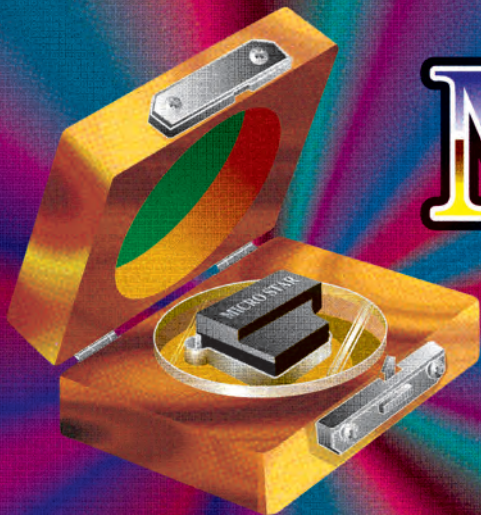


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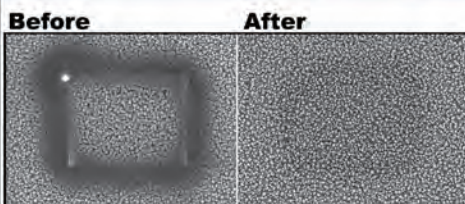
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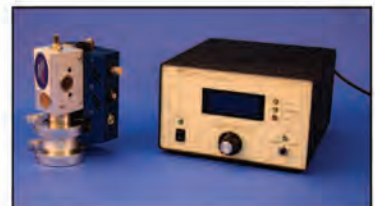
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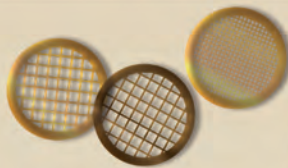


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